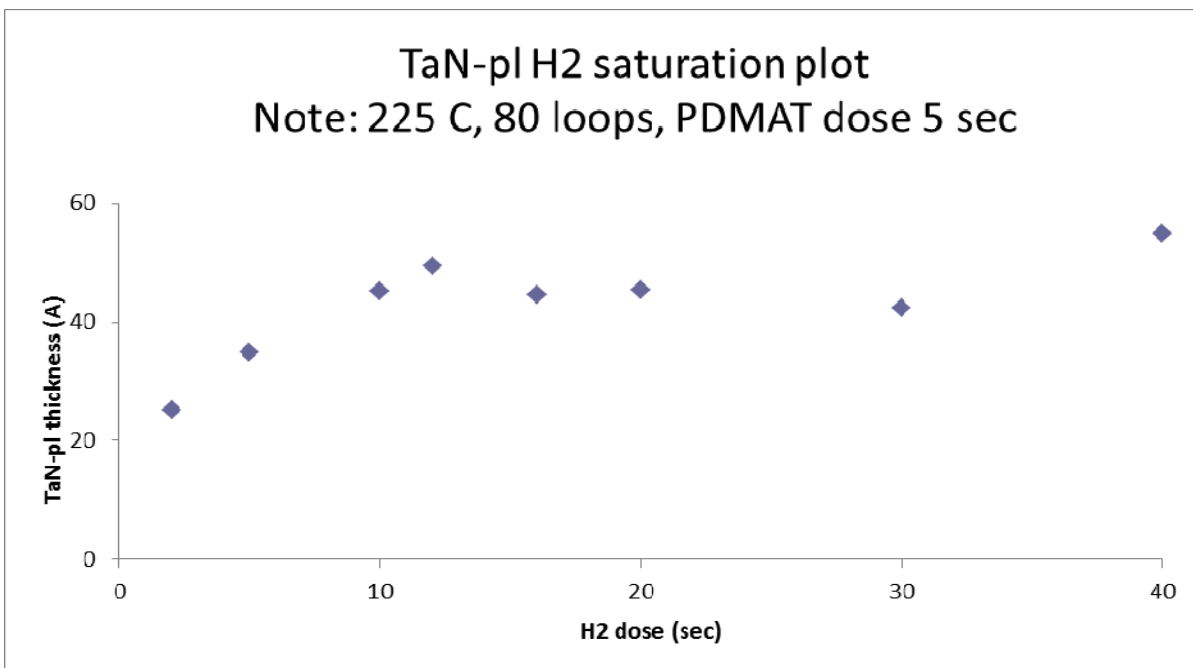
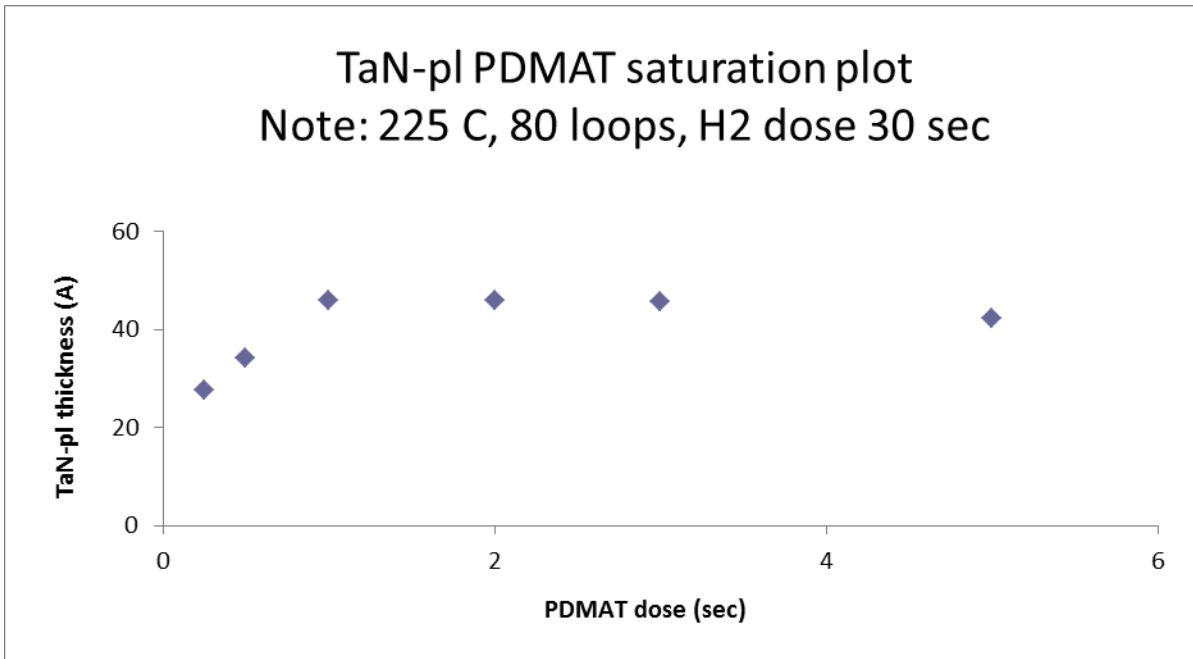


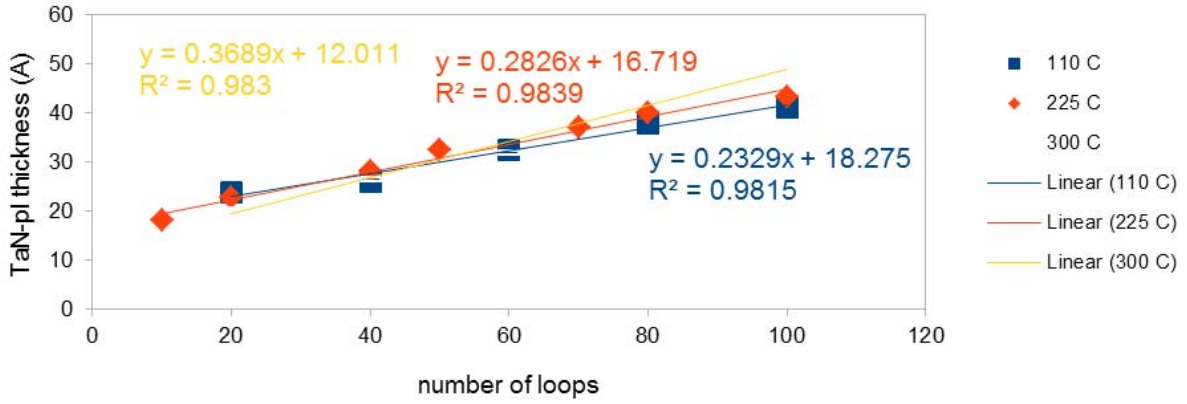
ALD TaN plasma characterization

1. PDMAT precursor and H₂ saturation plots

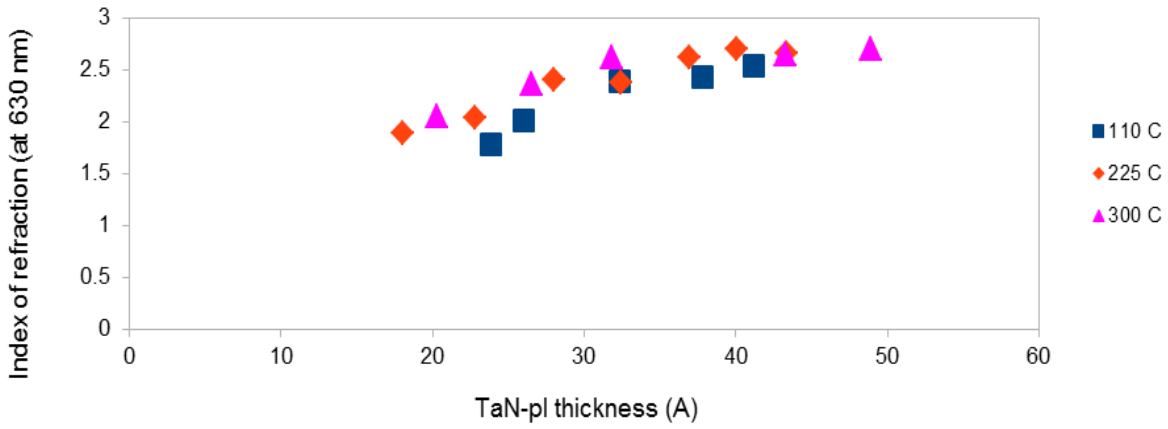


2. Linearity tests for TaOx films ranging 10-80 loops for temperatures 110C, 225C, and 300C

TaN-pl linearity plots



TaN-pl index of refraction v. thickness



TaN-pl thickness v. temperature

